

**Search Notes**

Application/Control No.

10/671,309

Examiner

Mark Kopec

Applicant(s)/Patent under  
Reexamination

HAYAKAWA ET AL.

Art Unit

1751

**SEARCHED**

Class	Subclass	Date	Examiner
252	512	9/16/2005	M.K.
252	513		
338	22R		
427	96		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
WEST	9/16/2005	M.K.
Inv. Name Search		